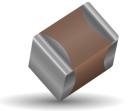
Y5V Dielectric General Specifications



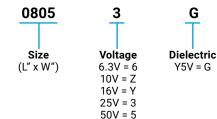


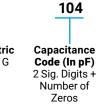
GENERAL DESCRIPTION

Y5V formulations are for general-purpose use in a limited temperature range. They have a wide temperature characteristic of +22% -82% capacitance change over the operating temperature range of -30°C to +85°C. These characteristics make Y5V ideal for decoupling applications within limited temperature range.



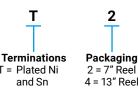
PART NUMBER (SEE PAGE 4 FOR COMPLETE PART NUMBER EXPLANATION)







Failure T = Plated Ni Rate A = Not

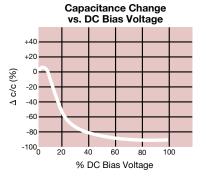


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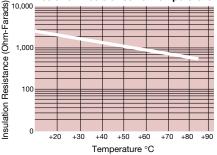
and Sn

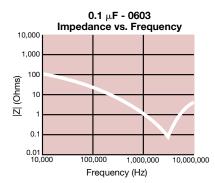


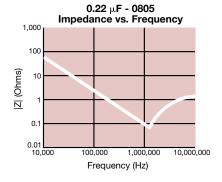
Temperature Coefficient +20 +10 0 % Δ Capacitance -10 -20 -30 -40 -50 -60 -70 -80 -35 +5 +25 +45 +65 +85 +105 +125 -55 -15 Temperature °C

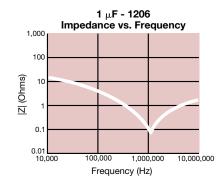


Insulation Resistance vs. Temperature 10,000









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Y5V Dielectric Specifications and Test Methods



Instruction Resistance whichever is less Image: Comparison of the seconds, w/charge and discharge current 1-3 seconds, w/charge and seconds, w/charge and, seconds, w/charge and seconds, w/charge and seconds	Parame	ter/Test	Y5V Specification Limits	Measuring Conditions							
Dissipation Factor ± 50% for 25W D0 rating ± 20% for 16V DC rating ± 20% for 16V DC rating ± 20% for 16V DC rating ± 12.5% for 16V DC rating Freq: 10.4K± 10%. Voltage 12Wms ± 2V For Cap > 10 µF, 0.5Vms @ 120Hz Insulation Resistance 10,000M0 or 500M0. µF, whichwer is less Charge device with rated voltage for 1.5 seconds, wicharge and discharge current @ 1000 temp/undity. Dielectric Strength No breakdown or visual defects Charge device with 20% of rated voltage for 1.5 seconds, wicharge and discharge current @ 1.5 seconds. Deflection: 2mm Test Time: 30 seconds Resistance to Stresses Appearance Uniside to Dissipation × 95% of each terminal should be covered with fresh 30db Dip device in eutectic solder at 230 ± 5°C for 5 0 ± 0.5 seconds Resistance to Solder hiet Appearance Variation × 10% Modefects. Step 1: -30°C ± 2° 30 ± 3 minutes Resistance to Solder hiet Appearance Variation No defects. Step 1: -30°C ± 2° 30 ± 3 minutes Resistance to Solder hiet Pactor Meets Initial Values (As Above) Step 1: -30°C ± 2° 30 ± 3 minutes Appearance Variation % studie feets Step 1: -30°C ± 2° 30 ± 3 minutes Appearance Variation Mo defects Step 1: -30°C ± 2° 30 ± 3 minutes Eator Fastor	Operating Temperature Range		-30°C to +85°C	Temperature Cycle Chamber							
Dissipation Factor - 2 70 % for 25V DC rating	Capacitance		Within specified tolerance	-							
Instantion resistance whichever is less @ toom temp/humidity Dielectric Strength No breakdown or visual defects Charge device with 25% of rade voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max) Resistance to Flexure Stresses Appearance Qapacitance statuation No defects s ± 30% Defection: 2mm Test Time: 30 seconds imm/sec Appearance Solderability 2 95% of each terminal should be covered with freah solder Dip device in eutectic solder at 230 ± 5°C for 5.0 ± 0.5 seconds Resistance to Solder Heat Appearance Variation No defects, <25% leaching of either end terminal capacitance sistenace Dip device in eutectic solder at 250% for 60 seconds. Store at room temperature for 24 ± 5 hours before measuring electrical properties. Resistance to Solder Heat Appearance No visual defects Step 1: -30°C ± 2° 30 ± 3 minutes Appearance Solder Heat Mo ets initial Values (As Above) Step 2: Room Temp 3 minutes Appearance Solder Heat Appearance No visual defects Step 1: -30°C ± 2° 30 ± 3 minutes 30 ± 3 minutes Appearance Solder Heat Meets Initial Values (As Above) Step 4: Room Temp 3 minutes Factor Factor Meets Initial Values (As Above) Step 4: Room Temp 3 minutes Appearance Variation <	Dissipati	on Factor	\leq 7.0% for 25V DC rating \leq 9.0% for 16V DC rating	Voltage: 1.0Vrms ± .2V							
Dielectric Strength No breakdown or visual defects 1-5 seconds, workange and discharge current limited to SD mA (max) Resistance to Fixure Stresses Appearance Qapacitance Variation s ± 30% Image: Stresses Deflection: 2mm Test Time: 30 seconds Solderability ± 95% of each terminal should be covered with resh solder Dip device in eutectic solder at 230 ± 5°C for 5.0 ± 0.5 seconds Dip device in eutectic solder at 230 ± 5°C for 5.0 ± 0.5 seconds Resistance to Solder Heat Capacitance Variation ≤ ±20% Dip device in eutectic solder at 260°C for 60 seconds. Store at noom temperature for 24 ± 2 for 5.0 ± 0.5 seconds Resistance to Solder Heat Displayion Factor Meets Initial Values (As Above) Dip device in eutectic solder at 260°C for 60 seconds. Store at noom temperature for 24 ± 2 for 5.0 ± 0.5 seconds Resistance to Solder Heat Capacitance Variation ≤ ±20% Step 1:-30°C ± 2° 30 ± 3 minutes Appearance Variation ≤ ±20% Step 2: Room Temp ≤ 3 minutes 3 minutes Appearance Variation ≤ ±20% Step 3: +85°C ± 2° 30 ± 3 minutes Appearance Variation ≤ ±20% Step 1:-30°C ± 2° 30 ± 3 minutes Load Life Appearance Variation ≤ ±20% Step 3: +85°C ± 2° 30 ± 3 minutes	Insulation Resistance			Charge device with rated voltage for 120 ± 5 sec @ room temp/humidity							
Capacitance Variation ≤ ±30% Deficition Thet Time: 30 seconds Piexure Stresses Dissipation Pactor Meets Initial Values (As Above) Immisec Immisec Solderability ≥ 95% of each terminal should be covered with fresh solder Dip device in eutectic solder at 230 ± 5°C for 50 ± 0.5 seconds Dip device in eutectic solder at 230 ± 5°C for 50 ± 0.5 seconds Resistance to Solder Heat Dissipation Factor Meets Initial Values (As Above) Dip device in eutectic solder at 260°C for 60 for 50 ± 0.5 seconds Dissipation Factor Meets Initial Values (As Above) Dip device in eutectic solder at 260°C for 60 for 50 ± 0.5 seconds Solder Heat Dissipation Factor Meets Initial Values (As Above) Dip device in eutectic solder at 260°C for 60 for 50 ± 0.5 seconds Appearance No visual defects Step 1: -30°C ± 2° 30 ± 3 minutes 3 minutes Capacitance Variation ≤ ±20% Step 2: Room Temp ≤ 3 minutes Dissipation Resistance Meets Initial Values (As Above) Step 4: Room Temp ≤ 3 minutes Dissipation Resistance Meets Initial Values (As Above) Step 4: Room Temp ≤ 3 minutes Load Life Dissipation Resistance ≤ Initial Values (As Above) <td< td=""><td>Dielectric</td><td>Strength</td><td>No breakdown or visual defects</td><td colspan="7">Charge device with 250% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max)</td></td<>	Dielectric	Strength	No breakdown or visual defects	Charge device with 250% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max)							
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Variation \$ ±20% Dissipation Meets Initial Values (As Above) Dip device in eutectic solder at 260°C for 60 seconds. Store at noom temperature for 24 ± 2 hours before measuring electrical properties. Insulation Resistance Meets Initial Values (As Above) Dielectric Dielectric Strength Meets Initial Values (As Above) Dielectric Appearance No visual defects Step 1: -30°C ± 2° 30 ± 3 minutes Capacitance ± ± 20% Step 2: Room Temp ≤ 3 minutes Dissipation Meets Initial Values (As Above) Step 3: +85°C ± 2° 30 ± 3 minutes Dissipation Meets Initial Values (As Above) Step 4: Room Temp ≤ 3 minutes Dissipation Meets Initial Values (As Above) Step 4: Room Temp ≤ 3 minutes Dielectric Meets Initial Values (As Above) Repeat for 5 cycles and measure after 24 ± 2 hours at noom temperature Capacitance ≤ ±30% Charge device with twice rated voltage in test chamber and stabilize at noot temperature for 24 ± 2 hours before measuring Insulation ≥ Initial Values (As Above) Remove from test chamber set at 85°C ± 2°C for 1000 hours (±48, -0) Insulation ≥ Initi	Resistance to Solder Heat	Appearance	No defects, <25% leaching of either end terminal								
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Load Humidity Appearance No visual defects Capacitance Variation ≤ ±30% Dissipation Factor ≤ Initial Value x 1.5 (See above) Insulation Resistance ≥ Initial Value x 0.1 (See Above) Dielectric Meets Initial Values (As Above)		Resistance	≥ Initial Value x 0.1 (See Above)								
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Load Humidity Dissipation Factor ≤ Initial Value x 1.5 (See above) (+48, -0) with rated voltage applied. Insulation Resistance ≥ Initial Value x 0.1 (See Above) Remove from chamber and stabilize at room temperature and humidity for 24 ± 2 hours before measuring.			≤ ±30%								
Insulation Resistance ≥ Initial Value x 0.1 (See Above) Remove from chamber and stabilize at room temperature and humidity for 24 ± 2 hours before measuring.			≤ Initial Value x 1.5 (See above)								
Dielectric Meets Initial Values (As Above)			≥ Initial Value x 0.1 (See Above)								
			Meets Initial Values (As Above)								



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PREFERRED SIZES ARE SHADED

SIZE 0201		01	0402					0603			0805				1206				1210					
Soldering Reflow Only		Reflow/Wave					Reflow/Wave				Reflow/Wave				ReflowMfeve				Reflow/Wave					
Packaging All Paper		All Paper					All Paper				Paper/Embossed				Paper/Embossed				Paper/Embossed					
(L) Length $\begin{array}{c} mm & 0.60 \pm 0.09 \\ (in.) & (0.024 \pm 0.004) \end{array}$		1.00 ± 0.10					1.60 ± 0.15				2.01 ± 0.20				3.20 ± 0.20				3.20 ± 0.20					
		(0.024 ±	0.004)	(0.040 ± 0.004					(0.063 ± 0.006)				(0.079 ± 0.008)				(0.126 ± 0.008)				(0.126 ± 0.008)			
W) Width	mm	0.30 ±	0.09	0.50 ± 0.10					.81 ± 0.15					1.25 ± 0.20				1.60 ± 0.20				2.50 ± 0.20		
w) wiath	(in.)	(0.011 ±	0.004)	(0.020 ± 0.004)					(0.032 ± 0.006)				(0.049 ± 0.008)				(0.063 ± 0.008)				(0.098 ± 0.008)			
(t) Terminal	mm	0.15 ±	0.05	0.25			± 0.15			0.35 ± 0.15			0.50 ± 0.25				0.50 ± 0.25				.50 ± 0.25			
(t) reminai	(in.)	(0.006 ± 0.002)		(0.010 ± 0.006			006)		(0.014 ± 0.006)			(0.020 ± 0.010)			0)	(0.020 ± 0.010)				(0.020 ± 0.010)				
	WVDC	6.3	10	6	10	16	25	50	10	16	25	50	10	16	25	50	10	16	25	50	10	16	25	50
Сар	820										1										\mathbf{x}		-w.	
(pF)	1000		Α																-	Ľ	<		5	<
	2200		Α																	(5		\mathcal{V}	T
	4700		Α							1	1									5	$ \downarrow $	1		
Сар	0.010	Α	Α																		-	T		
(µF)	0.022	Α																			. '.			
	0.047	Α				С																		
	0.10				С	С					G	G				K								
	0.22						1			G														
	0.33									G														
	0.47					С				G	G													
	1.0			С	С				G	G	J			N	N	Ν		М	М	М				Ν
	2.2				С				J					Ν	N				Κ	Q				
	4.7												Ν	N	N			Р	Q			N	Ν	
	10.0												Ν	Р			Q	Q	Х		Х	Q	Q	Ζ
	22.0																Q				Х	Z		
	47.0																							
	WVDC	6.3	10	6	10	16	25	50	10	16	25	50	10	16	25	50	10	16	25	50	10	16	25	50
SIZE 0201		01	0402						06	603			0805			1206				1210				
								· · · ·							Х									
Letter	Α	С	E	G J 0.90 0.94				K	М		N		Р		Q			Y	Z 2.79					
Max.	0.33	0.56	0.71			4	1.02	1.27		1.4)	1.52	1.78		2.2	9	2.54							
Thickness	(0.013)	(0.022)	(0.028)	(0.	.035)	(0.03	37)	(0.040)	(0.	050)	(0.05	5) ((0.060)	0.060) (0.070) (0.09			0) () (0.100) (0.110)						
			PAPER	1									EMB	BOSSE	ED									



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